Search Notes		

Application/Control No.	Applicant(s)/Patent unde Reexamination	or
10/693,736	YUAN ET AL.	
Examiner	Art Unit	
Chau Nguyen	2176	

	SEARCHED				
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715	530	3/15/2006	CN		
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715	511	03/17/2006	CN		
715	517	3/17/2006	CN		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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East Reports	03/15/2006 CN
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